

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

**U.S. PATENT DOCUMENTS**

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
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		Reddy et al., "A Data Compression Technique for Built-In Self-Test," <i>IEEE Trans. Computers</i> , Vol. 37, No. 9, pp. 1151-1156 (1988).	
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